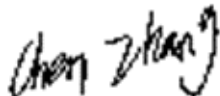


# TEST REPORT

Product Name: Smart Watch  
Trademark: N/A  
Model Number: SW/29, T48, T49, T12, E300, S2, S2P, S3, S5, S6, S6P, S6T, S7, S8, S9, S10, T40, T42, T41, T41S, T42S, T43, T33S, T30, T46S, T32S, T34S, T45S, T60, T66, T11, T68, T69, T90, TW26, TW27, E86, E87, E88, E89, E80, E66, E10, E90, E98, E200, E400, E500, E510, E600, E800, E900, E88pro, E88mini, F100, F12, F100, F18, F45, F60, F11, F12, F28, F80, M6, M5, M4S, X5  
Prepared For: Shenzhen Xiangmingda Technology Co., Ltd.  
Address: 8F, Block A, Building C4, No.3 Industrial Park (Tianlong Industrial Zone), Huangbu Community, Hangcheng Street, Baoan District, Shenzhen  
Manufacturer: Shenzhen Xiangmingda Technology Co., Ltd.  
Address: 8F, Block A, Building C4, No.3 Industrial Park (Tianlong Industrial Zone), Huangbu Community, Hangcheng Street, Baoan District, Shenzhen  
Prepared By: Shenzhen CTB Testing Technology Co., Ltd.  
Address: Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Community, Xinqiao Street, Baoan District, Shenzhen, Guangdong China  
Sample Received Date: Apr. 31, 2022  
Sample tested Date: Apr. 31, 2022 to Jun. 08, 2022  
Issue Date: Jun. 08, 2022  
Report No.: CTB220608002REX  
Test Standards: ETSI EN 301 489-1 V2.2.3 (2019-11)  
ETS EN 301 489-17 V3.2.4(2020-09)  
Test Results: PASS  
Remark: This is EMC test report.

Compiled by:

Chen Zheng

Reviewed by:

Arron Liu

Approved by:

Bin Mei / Director

The test report is effective only with both signature and specialized stamp. This result(s) shown in this report refer only to the sample(s) tested. Without written approval of Shenzhen CTB Testing Technology Co., Ltd. this report can't be reproduced except in full. The tested sample(s) and the sample information are provided by the client.

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(NOTE: N/A MEANS NOT APPLICABLE)

## 1. VERSION

Report No.	Issue Date	Description	Approved
CTB220608002REX	Jun. 8, 2022	Original	Valid

## 2. TEST SUMMARY

The Product has been tested according to the following specifications:

EMISSION		
Standard	Test Item	Test result
EN 55032	Conducted emissions from the AC mains power ports	Pass
EN 55032	Asymmetric mode conducted emissions	N/A <sup>1</sup>
EN 55032	Conducted differential voltage emissions	N/A <sup>2</sup>
EN 55032	Radiated emissions	Pass
EN 61000-3-2	Harmonic current emission(H)	Pass
EN 61000-3-3	Voltage fluctuations & flicker(F)	Pass

IMMUNITY		
Standard	Test Item	Test result
IEC 61000-4-2	Electrostatic discharge (ESD)	Pass
IEC 61000-4-3	Continuous RF electromagnetic field disturbances(RS)	Pass
IEC 61000-4-4	Electrical fast transients/burst (EFT)	Pass
IEC 61000-4-5	Surges	Pass
IEC 61000-4-6	Radio frequency, common mode	Pass
IEC 61000-4-11	Voltage dips and interruptions (DIPS)	Pass

Remark:

1. Applicable to ports listed above and intended to connect to cables longer than 3 m.
2. The Product has no antenna port.
3. The Product belongs to Class A, and its power is less than 75W, so it deems to fulfil this standard without testing.
4. The EUT is powered by the DC battery nly and has no antenna port, the test item is not applicable.

### 3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of  $k=2$ .

Test item	Value (dB)
Conducted Emission (150KHz-30MHz)	3.2
Radiated Emission(30MHz ~1000MHz)	4.8
Radiated Emission(1GHz ~6GHz)	4.9

## 4. PRODUCT INFORMATION AND TEST SETUP

### 4.1 Product Information

Model(s):	SW/29, T48, T49, T12, E300, S2, S2P, S3, S5, S6, S6P, S6T, S7, S8, S9, S10, T40, T42, T41, T41S, T42S, T43, T33S, T30, T46S, T32S, T34S, T45S, T60, T66, T11, T68, T69, T90, TW26, TW27, E86, E87, E88, E89, E80, E66, E10, E90, E98, E200, E400, E500, E510, E600, E800, E900, E88pro, E88mini, F100, F12, F100, F18, F45, F60, F11, F12, F28, F80, M6, M5, M4S, X5
Model Description:	All the model are the same circuit and RF module, only for model name. Test sample model: SW/29
Bluetooth Version:	Bluetooth V5.0
Hardware Version:	V1.0
Software Version:	V1.0
Operation Frequency:	Bluetooth: 2402-2480MHz
Max. RF output power:	Bluetooth: -1.48dBm
Type of Modulation:	Bluetooth: GFSK
Antenna installation:	Internal antenna
Antenna Gain:	1.0dBi
Ratings:	DC 5V charging from adapter Battery DC 3.7V

### 4.2 Test Setup Configuration

See test photographs attached in EUT TEST SETUP PHOTOGRAPHS for the actual connections between Product and support equipment.

### 4.3 Support Equipment

Item	Equipment	Mfr/Brand	Model/TypeNo.	SeriesNo.	Note
	AC adapter	SHENZHEN ENGINE ELECTRONIC CO.,LTD	EE-0501000E	N/A	AE

#### Notes:

1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

#### 4.4 Test Mode

Test item	Test Mode	Test Voltage
Conducted emissions from the AC mains power ports (150KHz-30MHz) Class B	Charging	AC 230V/50Hz
Radiated emissions(30MHz-6GHz)Class B	Charging	AC 230V/50Hz
	BT Linking	DC 3.7V
Electrostatic discharge (ESD) <input checked="" type="checkbox"/> Air Discharge: $\pm 2,4,8$ kV <input checked="" type="checkbox"/> Contact Discharge: $\pm 2,4$ kV <input checked="" type="checkbox"/> HCP & VCP: $\pm 2,4$ kV	Charging	AC 230V/50Hz
	BT Linking	DC 3.7V
Continuous RF electromagnetic field disturbances(RS) <input checked="" type="checkbox"/> 80MHz-6000MHz , 3V/m,80%	Charging	AC 230V/50Hz
	BT Linking	DC 3.7V
All test mode were tested and passed, only Conducted Emissions, Radiated Emissions Harmonic Current Emissions and Voltage Fluctuations and Flicker shows (1)sthe worst case mode which were recorded in this report.		



## 5. TEST FACILITY AND TEST INSTRUMENT USED

### 5.1 Test Facility

All measurement facilities used to collect the measurement data are located at Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Street, Baoan District, Shenzhen China. The site and apparatus are constructed in conformance with the requirements of ANSI C63.4 and CISPR 16-1-1 other equivalent standards.

### 5.2 Test Instrument Used

Continuous disturbance					
No.	Equipment	Manufacturer	Model No.	Serial No.	Calibrated until
1	AMN	ROHDE&SCHWARZ	ESH3-Z5	831551852	2022.08.05
2	Pulse limiter	ROHDE&SCHWARZ	ESH3Z2	357881052	2022.08.05
3	EMI TEST RECEIVER	ROHDE&SCHWARZ	ESCS30	834115/006	2022.08.05
4	Coaxial cable	ZDECL	Z302S	18091904	2022.08.05
5	AAN	Schwarzbeck	NTFM8158	183	2022.08.05
6	Communication test set	Agilent	E5515C	MY50102567	2022.08.16
7	Communication test set	R&S	CMW500	108058	2022.08.05
8	EZ-EMC	Frad	EMC-con3A1.1	/	/

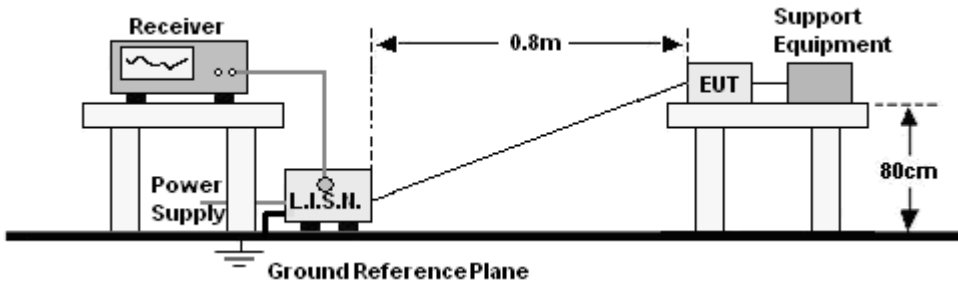
Radiated emission					
No.	Equipment	Manufacturer	Model No.	Serial No.	Calibrated until
1	Double Ridged Broadband Horn Antenna	Schwarzbeck	BBHA 9120D	1911	2022.08.08
2	TRILOG Broadband Antenna	Schwarzbeck	VULB 9168	869	2022.08.05
3	Amplifier	Agilent	8449B	3008A01838	2022.08.05
4	Amplifier	HP	8447E	2945A02747	2022.08.05
5	EMI TEST RECEIVER	ROHDE&SCHWARZ	ESPI7	100362	2022.08.05
6	Coaxial cable	ETS	RFC-SNS-100-NMS-80 NI	/	2022.08.05
7	Coaxial cable	ETS	RFC-SNS-100-NMS-20 NI	/	2022.08.05
8	Coaxial cable	ETS	RFC-SNS-100-SMS-20 NI	/	2022.08.05
9	Coaxial cable	ETS	RFC-NNS-100-NMS-300 NI	/	2022.08.05
10	Communication test set	Agilent	E5515C	MY50102567	2022.08.16
11	Communication test set	R&S	CMW500	108058	2022.08.05
12	EZ-EMC	Frad	EMC-con3A1.1	/	/

Electrostatic discharges					
No.	Equipment	Manufacturer	Model No.	Serial No.	Calibrated until
1	ESD Simulator	TESTQ	NSG437	329	2022.08.05
2	Communication test set	Agilent	E5515C	MY50102567	2022.08.16
3	Communication test set	R&S	CMW500	108058	2022.08.05

Radio frequency electromagnetic field					
No.	Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Signal Generator	Agilent	N5181A	2106070101	2022.08.05
2	Stacked Double Log.-Per. Antenna	SKET	STLP 9129 Plus	2106070106	2022.08.05
3	Switch Controller	SKET	RFSU-DC18G-4C	2106070105	2022.08.05
4	RF Power Meter	Agilent	U2001	2106070102	2022.08.16
5	E-Field Probe	Narda	EP-601	2106070107	2022.08.05
6	Power Amplifier	SKET	HAP-80M01G-250W	2106070103	2022.08.05
7	Power Amplifier	SKET	HAP-01G 06G-75W	2106070104	2022.08.05
8	Audio Analysis	R&S	UPV	2106070116	2022.08.16
9	Audio Output Matching Network	SKET	RCO Network	2106070117	2022.08.16
10	Communication test set	Agilent	E5515C	MY50102567	2022.08.16
11	Communication test set	R&S	CMW500	108058	2022.08.05
12	Test Software	SKET	/	/	/

## 6. CONDUCTED EMISSIONS

### 6.1 Block Diagram Of Test Setup



### 6.2 Limit

**Limits for Conducted emissions at the mains ports of Class B MME**

Frequency range (MHz)	Limits dB(μV)	
	Quasi-peak	Average
0,15 to 0,50	66 to 56*	56 to 46*
0,50 to 5	56	46
5 to 30	60	50

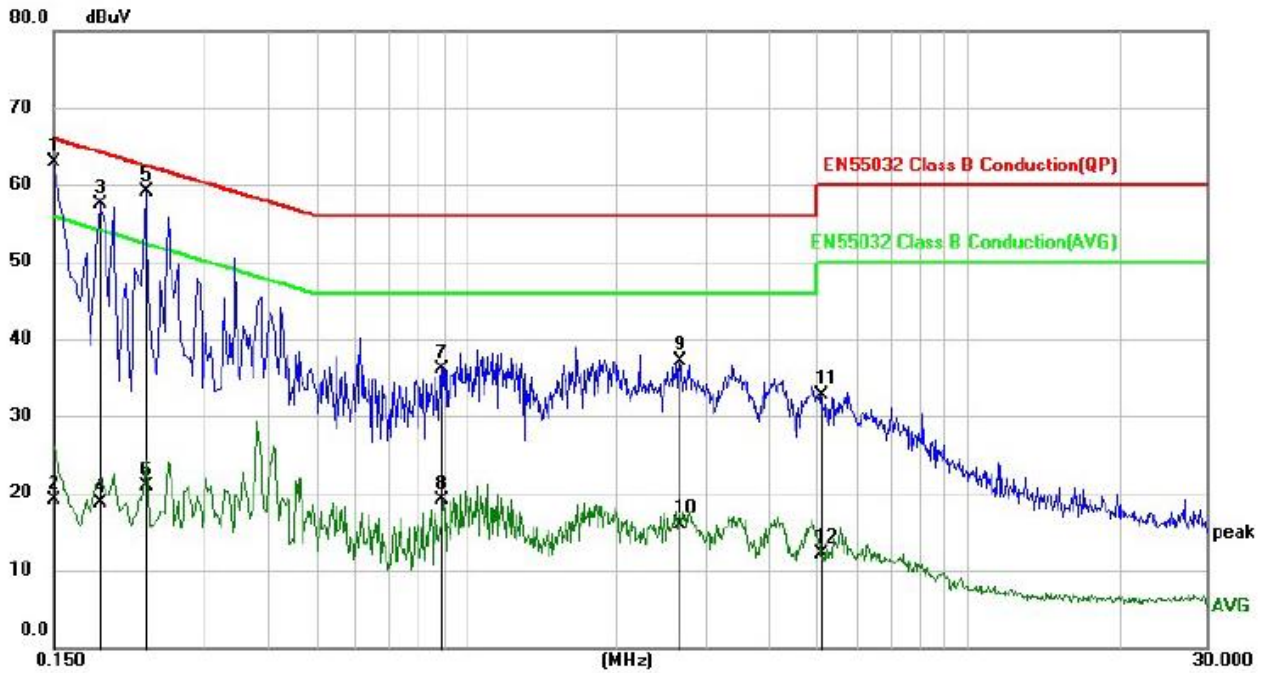
Notes: 1. \*Decreasing linearly with logarithm of frequency.  
2. The lower limit shall apply at the transition frequencies.

### 6.3 Test procedure

- The Product was placed on a nonconductive table 0.8m above the horizontal ground reference plane, and 0.4 m from the vertical ground reference plane, and connected to the main through Line Impedance Stability Network (L.I.S.N).
- The RBW of the receiver was set at 9 kHz in 150 kHz ~30MHz with Peak and AVG detector in Max Hold mode. Run the receiver's pre-scan to record the maximum disturbance generated from Product in all power lines in the full band.
- For each frequency whose maximum record was higher or close to limit, measure its QP and AVG values and record.

## 6.4 Test Result

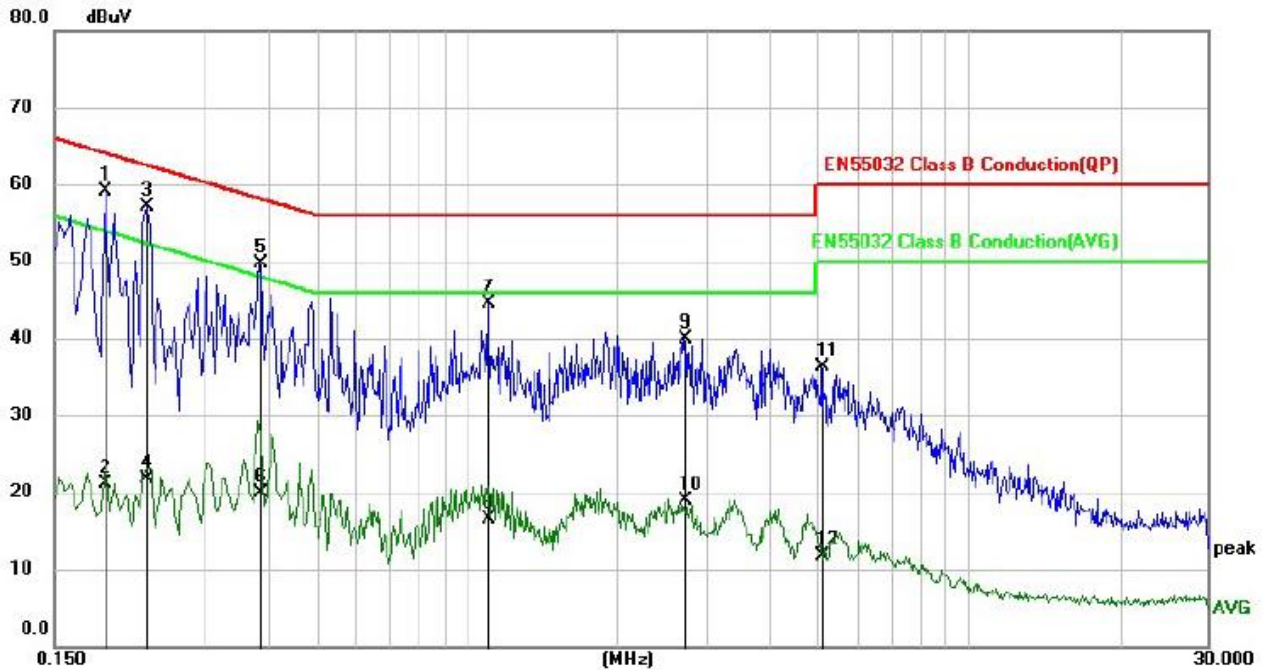
Temperature:	23℃	Relative Humidity:	54%
Pressure:	101kPa	Phase :	L
Test Mode	1(the worst data)	Remark:	N/A



No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV	Limit dBuV	Margin dB	Detector	Comment
1	*	0.1500	52.18	10.72	62.90	66.00	-3.10	QP	
2		0.1500	8.32	10.72	19.04	56.00	-36.96	AVG	
3		0.1860	46.74	10.70	57.44	64.21	-6.77	QP	
4		0.1860	8.03	10.70	18.73	54.21	-35.48	AVG	
5		0.2300	48.35	10.67	59.02	62.45	-3.43	QP	
6		0.2300	10.25	10.67	20.92	52.45	-31.53	AVG	
7		0.8900	25.47	10.60	36.07	56.00	-19.93	QP	
8		0.8900	8.42	10.60	19.02	46.00	-26.98	AVG	
9		2.6540	26.41	10.63	37.04	56.00	-18.96	QP	
10		2.6540	5.24	10.63	15.87	46.00	-30.13	AVG	
11		5.0980	22.14	10.65	32.79	60.00	-27.21	QP	
12		5.0980	1.51	10.65	12.16	50.00	-37.84	AVG	

Remark: Result=Reading +Factor  
Over Limit=Result –Limit

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Phase :	N
Test Mode	1(the worst data)	Remark:	N/A



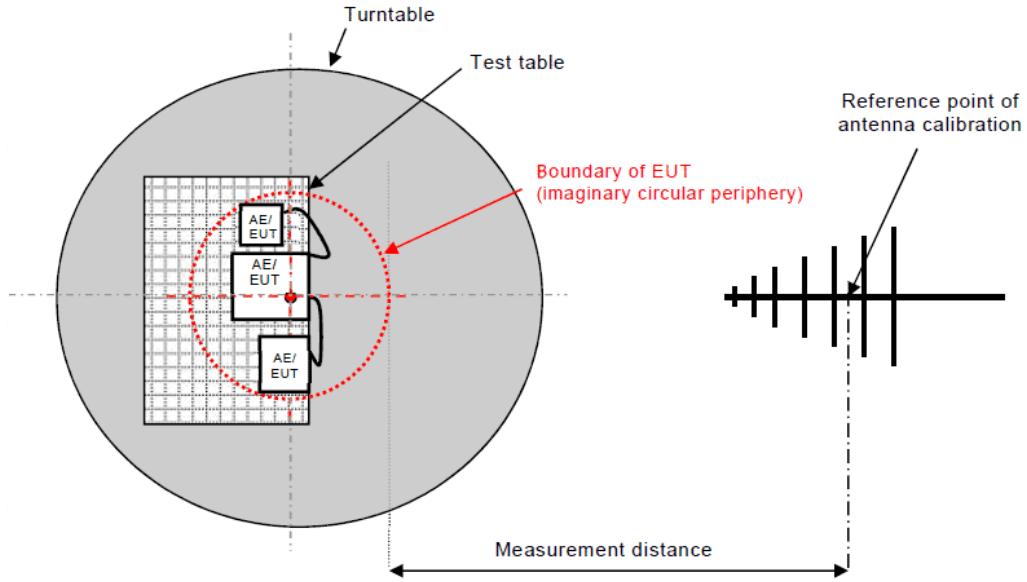
No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV	Limit dBuV	Margin dB	Detector	Comment
1	*	0.1900	48.34	10.70	59.04	64.04	-5.00	QP	
2		0.1900	10.34	10.70	21.04	54.04	-33.00	AVG	
3		0.2300	46.53	10.67	57.20	62.45	-5.25	QP	
4		0.2300	10.95	10.67	21.62	52.45	-30.83	AVG	
5		0.3860	39.13	10.59	49.72	58.15	-8.43	QP	
6		0.3860	9.40	10.59	19.99	48.15	-28.16	AVG	
7		1.1019	33.96	10.62	44.58	56.00	-11.42	QP	
8		1.1019	5.83	10.62	16.45	46.00	-29.55	AVG	
9		2.7139	29.31	10.63	39.94	56.00	-16.06	QP	
10		2.7139	8.29	10.63	18.92	46.00	-27.08	AVG	
11		5.1100	25.58	10.65	36.23	60.00	-23.77	QP	
12		5.1100	1.01	10.65	11.66	50.00	-38.34	AVG	

Remark: Result=Reading +Factor  
Over Limit=Result -Limit

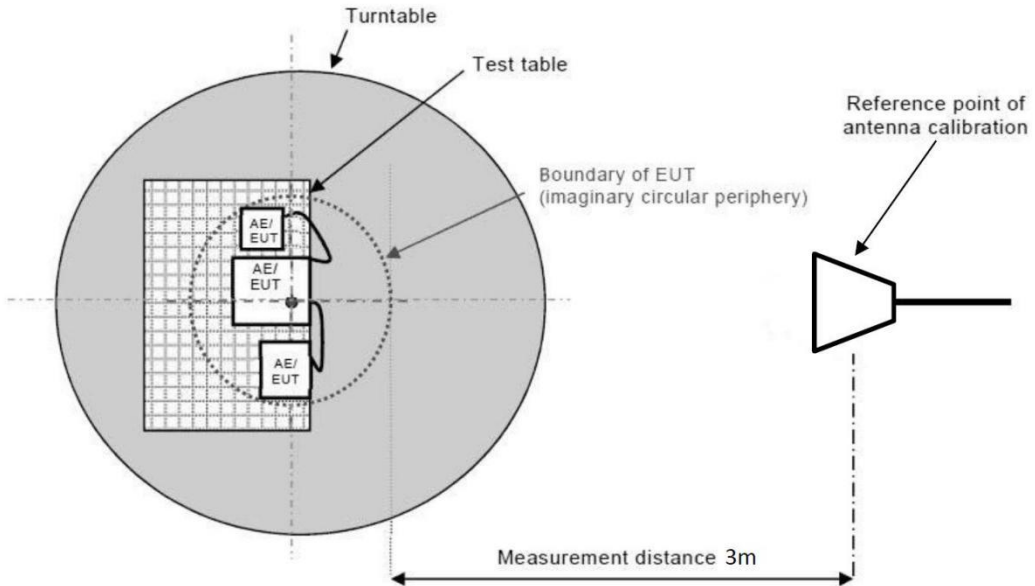
## 7. RADIATED EMISSIONS TEST

### 7.1 Block Diagram Of Test Setup

30MHz ~ 1GHz:



Above 1GHz:



### 7.2 Limits

#### Limits for radiated disturbance of Class B MME

Frequency (MHz)	Quasi-peak limits at 3m dB( $\mu$ V/m)
30-230	40
230-1000	47

Frequency (GHz)	limit above 1G at 3m dB( $\mu$ V/m)	
	Average	peak
1-3	50	70
3-6	54	74

**Note:** The lower limit shall apply at the transition frequencies.

### 7.3 Test Procedure

#### 30MHz ~ 1GHz:

- The Product was placed on the nonconductive turntable 0.8m above the ground in a semi anechoic chamber.
- Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 120 kHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied between 1~4 m in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- For each frequency whose maximum record was higher or close to limit, measure its QP value: vary the antenna's height and rotate the turntable from 0 to 360 degrees to find the height and degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to QP Detector and specified bandwidth with Maximum Hold Mode, and record the maximum value.

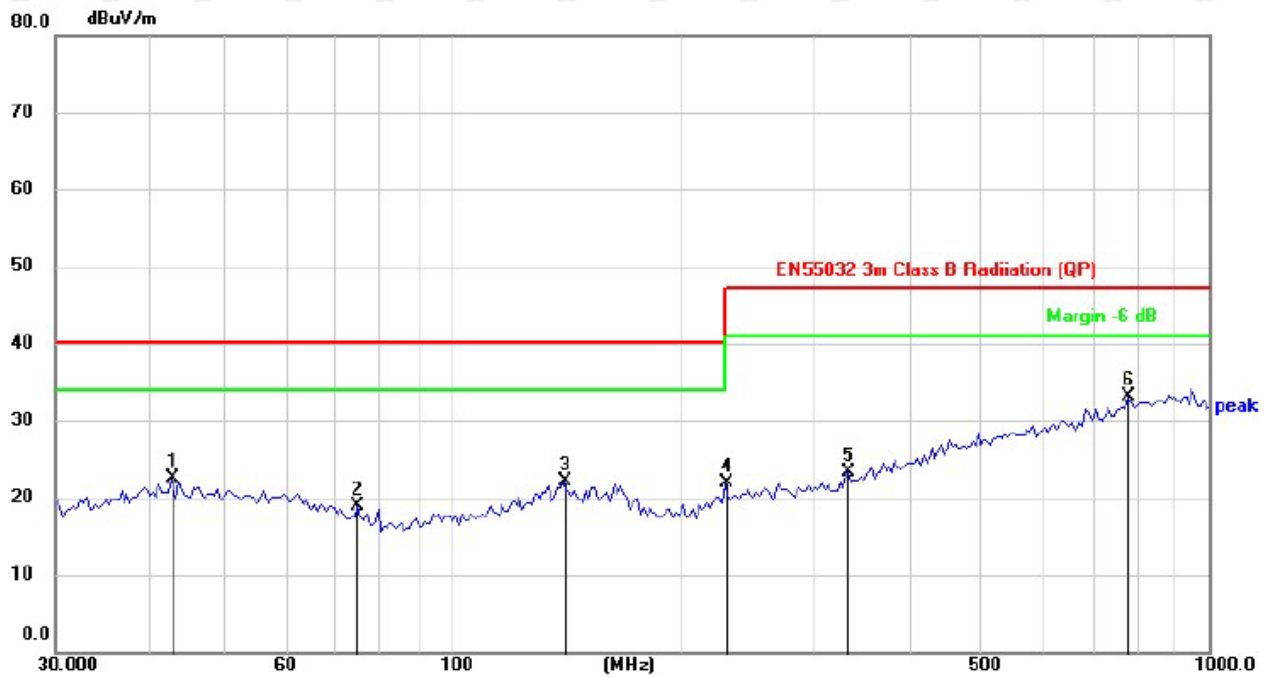
#### Above 1GHz:

- The Product was placed on the non-conductive turntable 0.8m above the ground in a full anechoic chamber..
- Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 1MHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- For each frequency whose maximum record was higher or close to limit, measure its AV value: rotate the turntable from 0 to 360 degrees to find the degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to AV value and specified bandwidth with Maximum Hold Mode, and record the maximum value.

## 7.4 Test Results

Below 1GHz

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Polarization :	Horizontal
Test Mode	1(the worst data)	Remark:	N/A

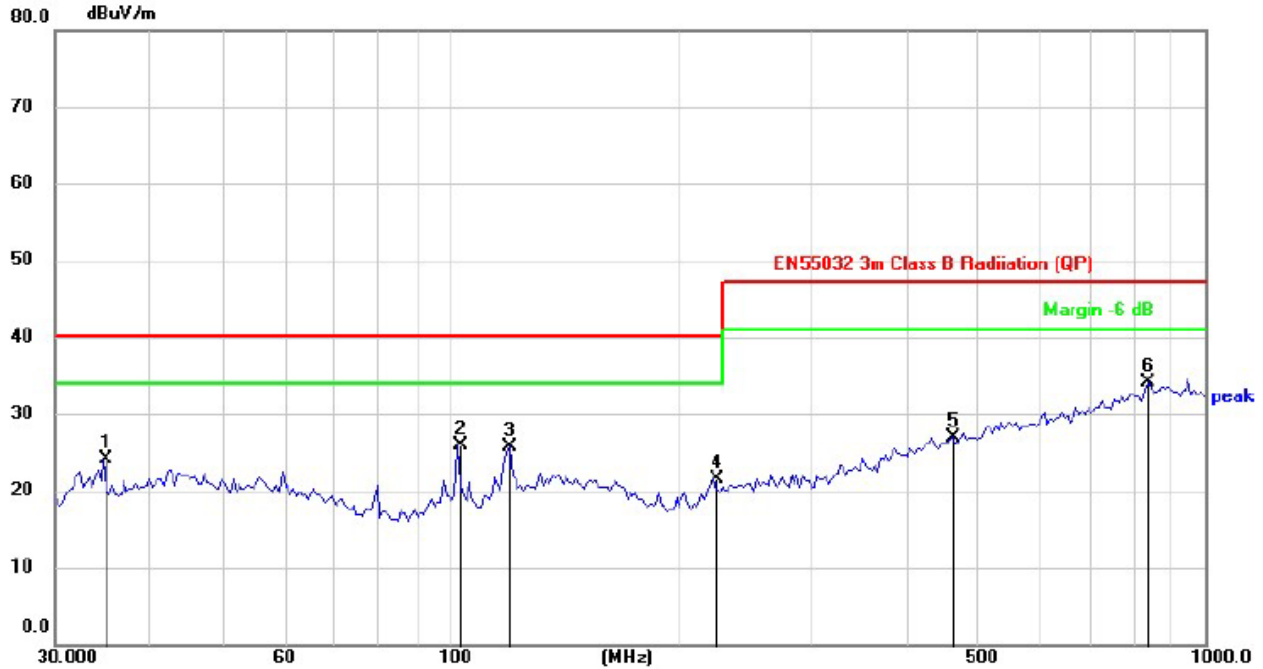


No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV/m	Limit dB/m	Over dB	Detector
1		42.6000	27.87	-5.37	22.50	40.00	-17.50	QP
2		75.3142	27.81	-8.90	18.91	40.00	-21.09	QP
3		140.3421	27.50	-5.44	22.06	40.00	-17.94	QP
4		229.2931	27.95	-5.95	22.00	40.00	-18.00	QP
5		334.2722	27.23	-4.01	23.22	47.00	-23.78	QP
6	*	782.3453	27.40	5.67	33.07	47.00	-13.93	QP

Remark: Result=Reading +Factor  
Over Limit=Result -Limit



Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Polarization :	Vertical
Test Mode	1(the worst data)	Remark:	N/A



No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV/m	Limit dB/m	Over dB	Detector
1		34.8212	30.58	-6.52	24.06	40.00	-15.94	QP
2		102.3597	34.41	-8.49	25.92	40.00	-14.08	QP
3		119.8556	32.66	-6.91	25.75	40.00	-14.25	QP
4		223.3415	27.88	-6.42	21.46	40.00	-18.54	QP
5		462.3455	27.12	-0.19	26.93	47.00	-20.07	QP
6	*	839.1818	27.96	6.10	34.06	47.00	-12.94	QP

Remark: Result=Reading +Factor  
Over Limit=Result -Limit

## Above 1GHz

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Polarization :	Horizontal
Test Mode	1(the worst data)	Remark:	N/A

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Det.
1	1967.90	45.92	1.43	47.35	70.00	-22.65	peak
2	1967.72	27.62	1.43	29.05	50.00	-20.95	AVG
3	3774.92	43.81	5.76	49.57	74.00	-24.43	peak
4	3777.28	26.55	5.76	32.30	54.00	-21.70	AVG
5	4839.30	42.52	9.60	52.12	74.00	-21.88	peak
6	4843.54	24.84	9.60	34.43	54.00	-19.57	AVG

Remark: Result=Reading +Factor  
Over Limit=Result -Limit

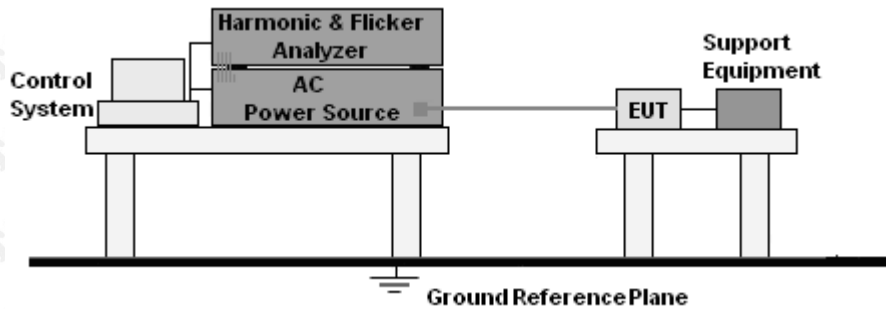
Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Polarization :	Vertical
Test Mode	1(the worst data)	Remark:	N/A

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Det.
1	1995.06	47.31	1.51	48.81	70.00	-21.19	peak
2	1994.31	29.85	1.51	31.36	50.00	-18.64	AVG
3	3807.35	47.02	5.88	52.90	74.00	-21.10	peak
4	3810.06	28.99	5.88	34.87	54.00	-19.13	AVG
5	4771.94	45.31	9.36	54.67	74.00	-19.33	peak
6	4770.61	27.52	9.36	36.87	54.00	-17.13	AVG

Remark: Result=Reading +Factor  
Over Limit=Result -Limit

## 8. HARMONIC CURRENT EMISSION(H)

### 8.1 Block Diagram of Test Setup



### 8.2 Limit

EN IEC 61000-3-2:2019 Clause 7.

### 8.3 Test Procedure

- a. The Product was placed on the top of a non-conductive table above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- b. The correspondent test program of test instrument to measure the current harmonics emanated from Product was chosen. The measure time shall be not less than the time necessary for the Product to be exercised.

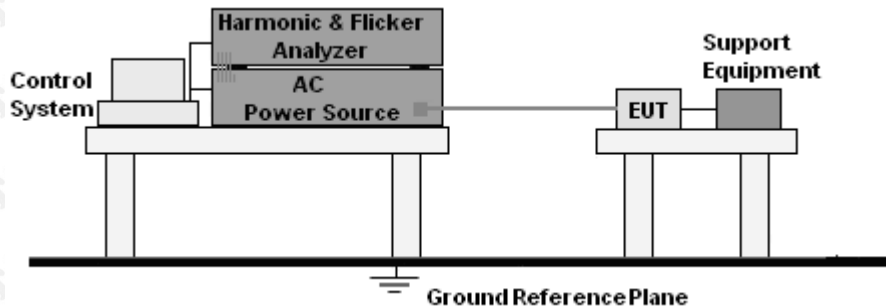
### Test Results

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Test Mode	1(the worst data)
Remark:	N/A	Test results	N/A

**Remark:**No limits apply for equipment with an active input power up to and including 75W.

## 9. VOLTAGE FLUCTUATIONS & FLICKER(F)

### 9.1 Block Diagram of Test Setup



### 9.2 Limit

EN 61000-3-3:2013/A1:2019 Clause 5.

### 9.3 Test Procedure

- The Product was placed on the top of a non-conductive table above the ground and operated to produce the most unfavorable sequence of voltage changes under normal operating conditions.
- During the flick test, the measure time shall include that part of whole operation cycle in which the Product produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

### 9.4 Test Results

Temperature:	23 °C	Relative Humidity:	54%
Pressure:	101kPa	Test Mode	1(the worst data)
Remark:	N/A	Test results	Pass

**Remark:** Due to the maximum r.m.s input current (including inrush current) does not exceed 20A, and the supply current after inrush in within a variation band of 1.5A, it's not applicable to test the manual switching.

Since the EUT is working in steady state with very low supply current, it will not cause any fluctuations and flicker on the supply system. Considering this, no flicker and voltage fluctuation test had been performed on the EUT, and the EUT can be deemed to comply with the standard accordingly without testing.

## 10. IMMUNITY TEST OF GENERAL THE PERFORMANCE CRITERIA

Product Standard	ETSI EN 301 489-1
	<p>The performance criteria are used to take a decision on whether a radio equipment passes or fails immunity tests.</p> <p>For the purpose of the present document two categories of performance criteria apply:</p> <ul style="list-style-type: none"> <li>•Performance criteria for continuous phenomena.</li> <li>•Performance criteria for transient phenomena.</li> </ul> <p>NOTE: Normally, the performance criteria depends upon the type of radio equipment and/or its intended application. Thus, the present document only contains general performance criteria commonly used for the assessment of radio equipment.</p>
<p>Performance criteria for continuous phenomena</p>	<p>During the test, the equipment shall:</p> <ul style="list-style-type: none"> <li>•continue to operate as intended;</li> <li>•not unintentionally transmit;</li> <li>•not unintentionally change its operating state;</li> <li>•not unintentionally change critical stored data.</li> </ul>
<p>Performance criteria for transient phenomena</p>	<p>For all ports and transient phenomena with the exception described below, the following applies:</p> <ul style="list-style-type: none"> <li>•The application of the transient phenomena shall not result in a change of the mode of operation (e.g. unintended transmission) or the loss of critical stored data.</li> <li>•After application of the transient phenomena, the equipment shall operate as intended.</li> </ul> <p>For surges applied to symmetrically operated wired network ports intended to be connected directly to outdoor lines the following criteria applies:</p> <ul style="list-style-type: none"> <li>•For products with only one symmetrical port intended for connection to outdoor lines, loss of function is allowed, provided the function is self-recoverable, or can be otherwise restored. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.</li> <li>•For products with more than one symmetrical port intended for connection to outdoor lines, loss of function on the port under test is allowed, provided the function is self-recoverable. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.</li> </ul>

According To EN 301489 -17standard, The General Performance Criteria As Following:

General performance criteria

The performance criteria are:

- performance criteria A for immunity tests with phenomena of a continuous nature;
- performance criteria B for immunity tests with phenomena of a transient nature;
- performance criteria C for immunity tests with power interruptions exceeding a certain time.

The equipment shall meet the minimum performance criteria as specified in the following clauses.

Table 1: Performance criteria

Criteria	During the test	After test (i.e. as a result of the application of the test)
<b>A</b>	Shall operate as intended. (see note). Shall be no loss of function. Shall be no unintentional transmissions.	Shall operate as intended. Shall be no degradation of performance. Shall be no loss of function. Shall be no loss of critical stored data.
<b>B</b>	May be loss of function.	Functions shall be self-recoverable. Shall operate as intended after recovering. Shall be no loss of critical stored data.
<b>C</b>	May be loss of function.	Functions shall be recoverable by the operator. Shall operate as intended after recovering. Shall be no loss of critical stored data.

NOTE: Operate as intended during the test allows a level of degradation in accordance with clause 6.2.2.

Minimum performance level

For equipment that supports a PER or FER, the minimum performance level shall be a PER or FER less than or equal to 10 %.

For equipment that does not support a PER or a FER, the minimum performance level shall be no loss of the wireless transmission function needed for the intended use of the equipment.

**Performance criteria for Continuous phenomena applied to Transmitters (CT)**

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply. The performance criteria A shall apply.

Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an ACKnowledgement (ACK) or NotACKnowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

**Performance criteria for Transient phenomena applied to Transmitters (TT)**

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply.

Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an acknowledgement (ACK) or not-acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

**Performance criteria for Continuous phenomena applied to Receivers (CR)**

The performance criteria A shall apply.

Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

**Performance criteria for Transient phenomena applied to Receivers (TR)**

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration for which performance criteria C shall apply.

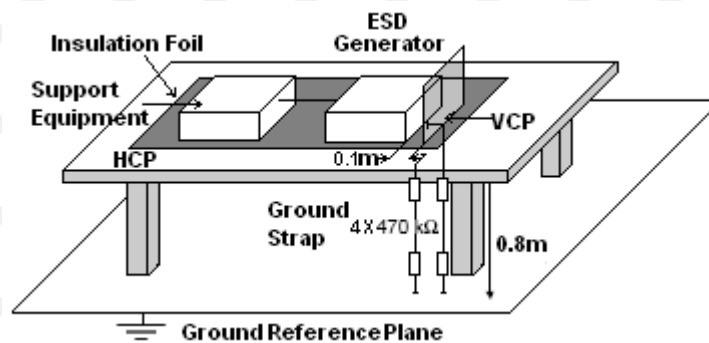
Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

## 11. ELECTROSTATIC DISCHARGE (ESD)

### 11.1 Test Specification

<b>Test Port</b>	: Enclosure port
<b>Discharge Impedance</b>	: 330 ohm / 150 pF
<b>Discharge Mode</b>	: Single Discharge
<b>Discharge Period</b>	: one second between each discharge

### 11.2 Block Diagram of Test Setup



### 11.3 Test Procedure

- Electrostatic discharges were applied only to those points and surfaces of the Product that are accessible to users during normal operation.
- The test was performed with at least ten single discharges on the pre-selected points in the most sensitive polarity.
- The time interval between two successive single discharges was at least 1 second.
- The ESD generator was held perpendicularly to the surface to which the discharge was applied and the return cable was at least 0.2 meters from the Product.
- Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.
- Air discharges were applied with the round discharge tip of the discharge electrode approaching the Product as fast as possible (without causing mechanical damage) to touch the Product. After each discharge, the ESD generator was removed from the Product and re-triggered for a new single discharge. The test was repeated until all discharges were complete.
- At least ten single discharges (in the most sensitive polarity) were applied to the Horizontal Coupling Plane at points on each side of the Product. The ESD generator was positioned vertically at a distance of 0.1 meters from the Product with the discharge electrode touching the HCP.



h. At least ten single discharges (in the most sensitive polarity) were applied to the center of one vertical edge of the Vertical Coupling Plane in sufficiently different positions that the four faces of the Product were completely illuminated. The VCP (dimensions 0.5m x 0.5m) was placed vertically to and 0.1 meters from the Product.

#### 11.4 Test Results

Temperature :	23°C	Relative Humidity :	54%
Pressure :	101kPa	Test Mode :	Mode1, Mode2

Discharge Method	Discharge Position	Voltage (±kV)	Min. No. of Discharge per polarity (Each Point)	Performance Criterion
Contact Discharge	Conductive Surfaces	4	10	A
	Indirect Discharge HCP	4	10	A
	Indirect Discharge VCP	4	10	A
Air Discharge	Slots, Apertures, and Insulating Surfaces	8	10	A

Note: A: No performance degradation during test.  
 B: During the test, the EUT shut down, after the test, it reset by itself.  
 C: During the test, the EUT shut down, after the test, it reset by user.

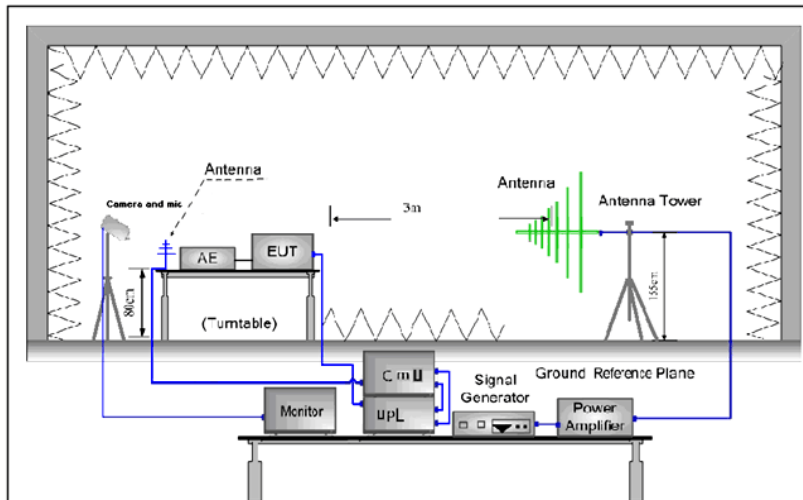
## 12. CONTINUOUS RF ELECTROMAGNETIC FIELD DISTURBANCES(RS)

### 12.1 Test Specification

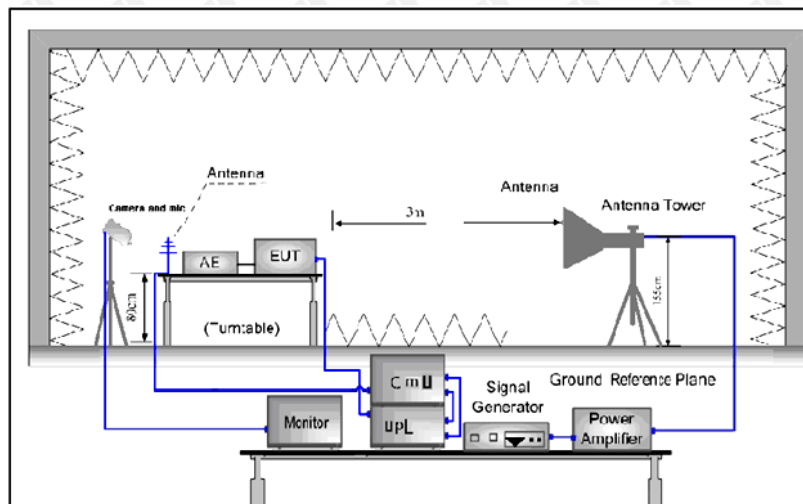
<b>Test Port</b>	: Enclosure port
<b>Step Size</b>	: 1%
<b>Modulation</b>	: 1kHz, 80% AM
<b>Dwell Time</b>	: 1 second
<b>Polarization</b>	: Horizontal & Vertical

### 12.2 Block Diagram of Test Setup

Below 1GHz:



Above 1GHz:



### 12.3 TestProcedure

- a. The testing was performed in a fully-anechoic chamber. The transmit antenna was located at a distance of 3 meters from the Product.
- b. The frequency range is swept from 80MHz to 6000MHz, with the signal 80% amplitude modulated with a 1 kHz sine wave, and the step size was 1%.
- c. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond, but should not exceed 5 s at each of the frequencies during the scan.
- d. The test was performed with the Product exposed to both vertically and horizontally polarized fields on each of the four sides.
- e. For Broadcast reception function: Group 2 not apply in this test.

### 12.4 Test Results

Temperature :	23°C	Relative Humidity :	54%
Pressure :	101kPa	Test Mode :	Mode1, Mode2

Frequency	Position	Field Strength (V/m)	PerformanceCriterion
80 - 6000MHz	Front, Right, Back, Left	3	A

Note: A: No performance degradation during test.

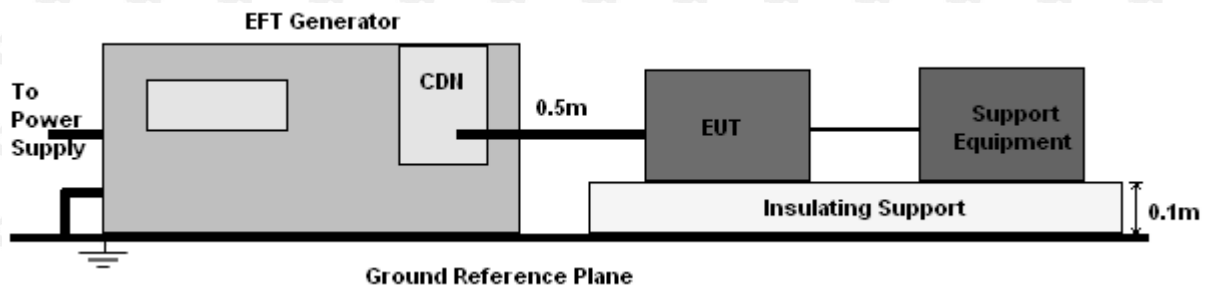
## 13. ELECTRICAL FAST TRANSIENTS/BURST (EFT)

### 13.1 Test Specification

<b>Test Port</b>	: input a.c. power port
<b>Impulse Frequency</b>	: 5 kHz
<b>Impulse Wave-shape</b>	: 5/50 ns
<b>Burst Duration</b>	: 15 ms
<b>Burst Period</b>	: 300 ms
<b>Test Duration</b>	: 2 minutes per polarity

### 13.2 Block Diagram of EUT Test Setup

For input a.c.power port:



### 13.3 Test Procedure

- The Product and support units were located on a non-conductive table above ground reference plane.
- A 0.5m-long power cord was attached to Product during the test.

## 13.4 Test Results

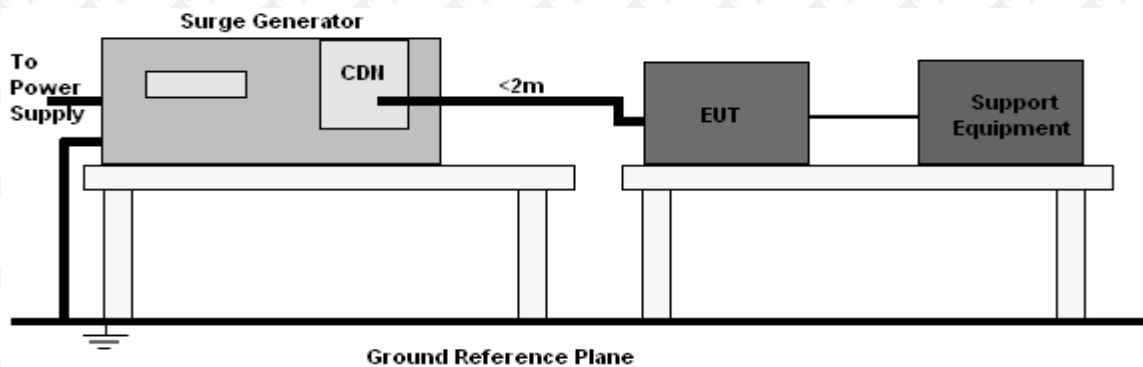
N/A

## 14. SURGES IMMUNITY TEST

### 14.1 Test Specification

<b>Test Port</b>	: input a.c. power port
<b>Wave-Shape</b>	: Open Circuit Voltage - 1.2 / 50 us Short Circuit Current - 8 / 20 us
<b>Pulse Repetition Rate</b>	: 1 pulse / min.
<b>Phase Angle</b>	: 0° / 90° / 180° / 270°
<b>Test Events</b>	: 5 pulses (positive & negative) for each polarity

### 14.2 Block Diagram of EUT Test Setup



### 14.3 Test Procedure

- a. The surge is to be applied to the Product power supply terminals via the capacitive coupling network. Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines, and to provide sufficient decoupling impedance to the surge wave.
- b. The power cord between the Product and the coupling/decoupling networks shall be 2 meters in length (or shorter). Interconnection line between the Product and the coupling/decoupling networks shall be 2 meters in length (or shorter).

### 14.4 Test Result

N/A

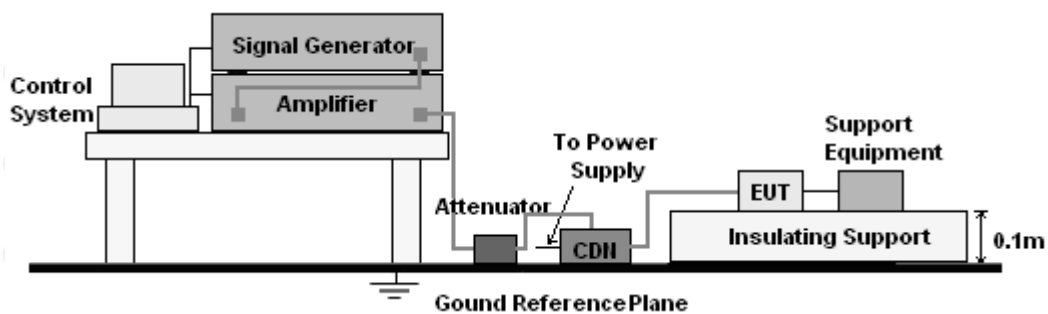
## 15. CONTINUOUS INDUCED RF DISTURBANCES (CS)

### 15.1 Test Specification

<b>Test Port</b>	: input a.c.power port
<b>Step Size</b>	: 1%
<b>Modulation</b>	: 1kHz, 80% AM
<b>Dwell Time</b>	: 1 second

### 15.2 Block Diagram of EUT Test Setup

For input a.c. power port:



### 15.3 Test Procedure

For input a.c.power port:

- The Product and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- The frequency range is swept from 150 kHz to 10MHz, 10MHz to 30MHz, 30MHz to 80MHz with the signal 80% amplitude modulated with a 1 kHz sine wave, and the step size was 1% of fundamental.
- The dwell time at each frequency shall be not less than the time necessary for the Product to be able to respond.

### 15.4 Test Result

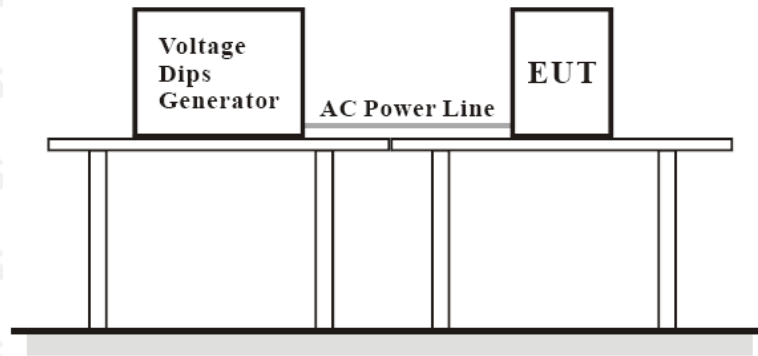
N/A

## 16. VOLTAGE DIPS AND INTERRUPTIONS (DIPS)

### 16.1 Test Specification

Test Port	: input a.c. power port
Phase Angle	: 0°, 180°
Test cycle	: 3 times

### 16.2 Block Diagram of EUT Test Setup



### 16.3 Test Procedure

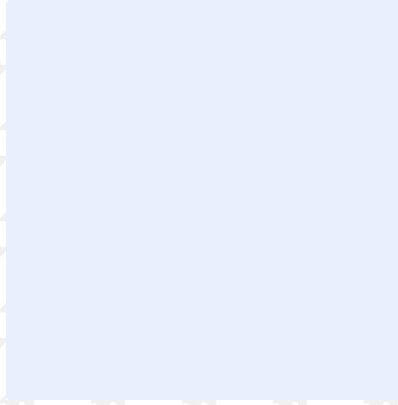
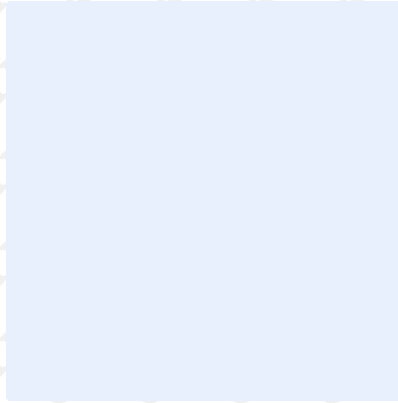
- The Product and support units were located on a non-conductive table above ground floor.
- Set the parameter of tests and then perform the test software of test simulator.
- Conditions changes to occur at 0 degree crossover point of the voltage waveform.

### 16.4 Test Result

N/A



17.

**EUT PHOTOGRAPHS****External Photos**  
**EUT Photo 1****EUT Photo 2**

**EUT Photo 3**

**EUT Photo 4**

**EUT Photo 5**

**EUT Photo 6**

**Internal photos**  
**EUT Photo 1**

**EUT Photo 2**

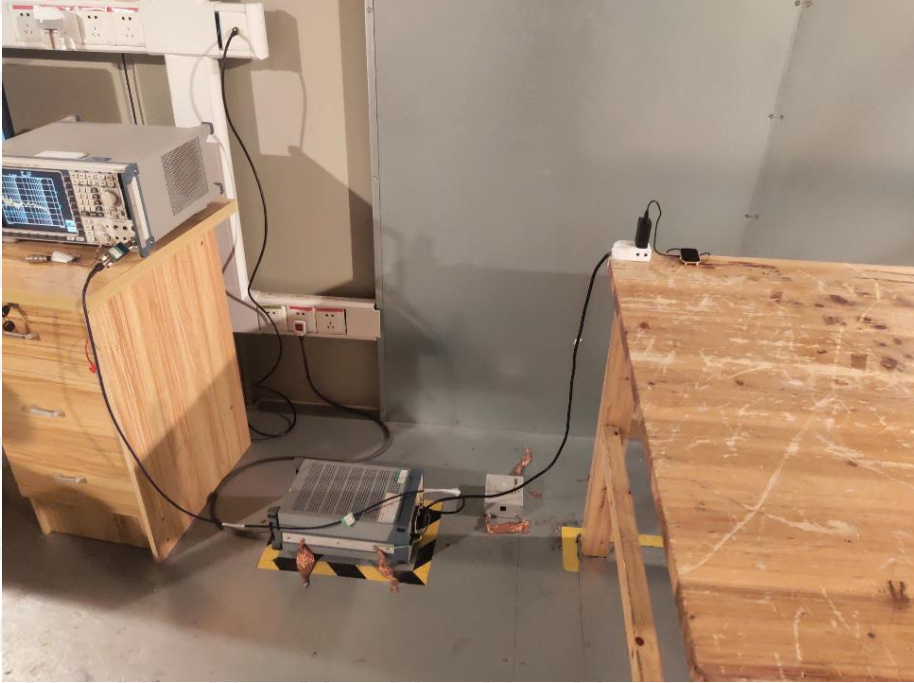
**EUT Photo 3**

**EUT Photo 4**

**EUT Photo 5**

## 18. EUT TEST SETUP PHOTOGRAPHS

### Conducted emissions



### Radiated emissions below 1G



ESD



RS



\*\*\*\*\* END OF REPORT \*\*\*\*\*

## CERTIFICATE OF CONFORMITY

**EU - The Radio Equipment Directive (RED) -  
No. : CTB220608002REX-ZS**

**Applicant** : Shenzhen Xiangmingda Technology Co., Ltd.  
**Address** : 8F, Block A, Building C4, No.3 Industrial Park (Tianlong Industrial Zone),  
Huangbu Community, Hangcheng Street, Baoan District, Shenzhen  
**Manufacturer** : Shenzhen Xiangmingda Technology Co., Ltd.  
**Address** : 8F, Block A, Building C4, No.3 Industrial Park (Tianlong Industrial Zone),  
Huangbu Community, Hangcheng Street, Baoan District, Shenzhen  
**Product** : Smart Watch  
**Trade Name** : N/A  
**Model(s)** : SW/29, T48, T49, T12, E300, S2, S2P, S3, S5, S6, S6P, S6T, S7, S8, S9,  
S10, T40, T42, T41, T41S, T42S, T43, T33S, T30, T46S, T32S, T34S,  
T45S, T60, T66, T11, T68, T69, T90, TW26, TW27, E86, E87, E88, E89,  
E80, E66, E10, E90, E98, E200, E400, E500, E510, E600, E800, E900,  
E88pro, E88mini, F100, F12, F100, F18, F45, F60, F11, F12, F28, F80,  
M6, M5, M4S, X5

The tests that base on the above designated product Complies with the essential requirements of Directive 2014/53/EU relating to Electrical Equipment designed for use within Radio and telecommunications terminal equipment.

The test results apply only to the particular sample tested and the applicative tests carried out. The CE markings as shown below can be affixed on product after manufacturer carry out all stipulation activities integrally of above mentioned Regulation (Directive) and preparation of necessary technical documentation as well as the conformity declaration.

This statement is based on a single evaluation of sample of above mentioned product. It does not imply an assessment of the whole production process.

Other relevant Regulation (Directive) requirement have to be observed.



Bl. Mei (Director)

Jun. 23, 2022



**Shenzhen CTB Testing Technology Co., Ltd**

Add: Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Community, Xinqiao Street, Baoan District, Shenzhen, Guangdong, China.

Web: <http://www.ctb-lab.net> Tel: 4008-707-283 Email: [ctb@ctb-lab.net](mailto:ctb@ctb-lab.net)



## CERTIFICATE OF CONFORMITY

EU - The Radio Equipment Directive (RED) -  
No. : CTB220608002REX-ZS

Category	Test Standards	Test Report No.
Health and Safety (Article 3.1a)	EN IEC 62368-1:2020+A11:2020	CTB220622011RSX
	EN 62479:2010 EN 50663:2017	CTB220607005RHX
EMC (Article 3.1b)	ETSI EN 301 489-1 V2.2.3 (2019-11)	CTB220608002REX
	ETSI EN 301 489-17 V3.2.4(2020-09)	
Radio Aspects (Article 3.2)	ETSI EN 300 328 V2.2.2 (2019-07)	CTB220606026RFX CTB220609003RFX

The tests that base on the above designated product Complies with the essential requirements of Directive 2014/53/EU relating to Electrical Equipment designed for use within Radio and telecommunications terminal equipment.

The test results apply only to the particular sample tested and the applicative tests carried out. The CE markings as shown below can be affixed on product after manufacturer carry out all stipulation activities integrally of above mentioned Regulation (Directive) and preparation of necessary technical documentation as well as the conformity declaration.

This statement is based on a single evaluation of sample of above mentioned product. It does not imply an assessment of the whole production process.

Other relevant Regulation (Directive) requirement have to be observed.



Bin Mei (Director)

Jun. 23, 2022

CERTIFICATE ◆ CERTIFICATE ◆ CERTIFICATE



**Shenzhen CTB Testing Technology Co., Ltd**

Add: Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Community, Xinqiao Street, Baoan District, Shenzhen, Guangdong, China.

Web: <http://www.ctb-lab.net> Tel: 4008-707-283 Email: [ctb@ctb-lab.net](mailto:ctb@ctb-lab.net)





# TEST REPORT

Page 1 of 9

REPORT No.: CTB220623010CX

**Applicant:** Shenzhen Xiangmingda Technology Co., Ltd.  
**Address:** 8F, Block A, Building C4, No.3 Industrial Park (Tianlong Industrial Zone), Huangbu Community, Hangcheng Street, Baoan District, Shenzhen




**Manufacturer:** Shenzhen Xiangmingda Technology Co., Ltd.  
**Address:** 8F, Block A, Building C4, No.3 Industrial Park (Tianlong Industrial Zone), Huangbu Community, Hangcheng Street, Baoan District, Shenzhen

The following samples were submitted and identified on behalf of the clients as:

**Sample name:** Smart Watch  
**Brand:** /  
**Model(s):** See next pages  
**Batch No.:** /  
**Sample received date:** June 10,2022  
**Testing period:** June 10,2022 to June 23,2022  
**Test Method:** Please refer to next page(s).  
**Test Result:** Please refer to next page(s).

\*\*\*\*\*  
**Result Summary :**

Test Requested	Conclusion
European Directive 2011/65/EU and amendment (EU) 2015/863 on the restriction of the use of certain hazardous substances in electrical and electronic equipment	PASS

<b>Tested By:</b> 	<b>Check By:</b> 	<b>Approve By:</b> 
--	---	---

**Date: June 23, 2022**

Note: If there is any objection to the inspection results in this report, please submit a written report to the company within 15 days from the date of receiving the report. The test report is effective only with both signature and specialized stamp. This result(s) shown in this report refer only to the sample(s) tested. Without written approval of Shenzhen CTB Testing Technology Co., Ltd. this report can't be reproduced except in full. The tested sample(s) and the sample information are provided by the client. "\*" indicates the testing items were fulfilled by subcontracted lab. "#" indicates the items are not in CNAS accreditation scope.

Series models as below (page 2) :

<b>Model(s)</b>	:	SW/29, T48, T49, T12, E300, S2, S2P, S3, S5, S6, S6P, S6T, S7, S8, S9, S10, T40, T42, T41, T41S, T42S, T43, T33S, T30, T46S, T32S, T34S, T45S, T60, T66, T11, T68, T69, T90, TW26, TW27, E86, E87, E88, E89, E80, E66, E10, E90, E98, E200, E400, E500, E510, E600, E800, E900, E88pro, E88mini, F100, F12, F100, F18, F45, F60, F11, F12, F28, F80, M6, M5, M4S, X5
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**Test Method:**

**A. Screening test by XRF spectroscopy**

XRF screening limits for regulated elements according to IEC 62321-3-1:2013

Element	Screening limit / mg/kg		MDL	
	Polymers and metals	Composite material	Polymers	Other material
<b>Pb</b>	$BL \leq (700-3\sigma) < X < (1300+3\sigma)$ $\leq OL$	$BL \leq (500-3\sigma) < X < (1500+3\sigma)$ $\leq OL$	10mg/kg	50mg/kg
<b>Cd</b>	$BL \leq (70-3\sigma) < X < (130+3\sigma)$ $\leq OL$	$LOD \leq (50-3\sigma) < X < (150+3\sigma)$ $\leq OL$	10mg/kg	50mg/kg
<b>Hg</b>	$BL \leq (700-3\sigma) < X < (1300+3\sigma)$ $\leq OL$	$BL \leq (500-3\sigma) < X < (1500+3\sigma)$ $\leq OL$	10mg/kg	50mg/kg
<b>Cr</b>	$BL \leq (700-3\sigma) < X$	$BL \leq (500-3\sigma) < X$	10mg/kg	50mg/kg
<b>Br</b>	$BL \leq (300-3\sigma) < X$ (non-metal only)	$BL \leq (250-3\sigma) < X$	10mg/kg	50mg/kg

**B. Chemical Test**

Test Item(s)	Test Method	Analysis Equipment(s)	MDL	Limit
Lead (Pb)	IEC 62321-5:2013	ICP-OES	10mg/kg	1000mg/kg
Cadmium (Cd)	IEC 62321-5:2013	ICP-OES	10mg/kg	100mg/kg
Mercury (Hg)	IEC 62321-4:2013+AMD1:2017	ICP-OES	10mg/kg	1000mg/kg
Hexavalent Chromium Cr(VI)	IEC 62321-7-1:2015 & IEC 62321-7-2:2017	UV-VIS	10mg/kg	1000mg/kg
Polybrominated Biphenyls (PBBs)	IEC 62321-6:2015	GC-MS	10mg/kg	1000mg/kg
Polybrominated Diphenyl Ethers (PBDEs)	IEC 62321-6:2015	GC-MS	10mg/kg	1000mg/kg
Dibutyl Phthalate	IEC 62321-8:2017	GC-MS	30mg/kg	1000mg/kg
Benzylbutyl Phthalate	IEC 62321-8:2017	GC-MS	30mg/kg	1000mg/kg
Bis-(2-ethylhexyl)Phthalate	IEC 62321-8:2017	GC-MS	30mg/kg	1000mg/kg
Diisobutyl phthalate	IEC 62321-8:2017	GC-MS	30mg/kg	1000mg/kg

**Tested material list**

Sample No.	Description
1	Black glass (display)
2	Rose gold plated metal frame
3	White plastic (display)
4	Transparent plastic (display)
5	Black plastic (display)
6	Black plastic case (dial)
7	Black PCB
8	Yellow plastic film
9	Silver magnet
10	Silver metal screws

Note: test samples were specified by applicant.



# TEST REPORT

Page 4 of 9

REPORT No. : CTB220623010CX

## Test Result(s):

No.	XRF screening Result					Chemical confirm Result (mg/kg)	Remark	Conclusion
	Pb	Cd	Hg	Cr	Br			
1	BL	BL	BL	BL	BL	---	---	<b>PASS</b>
2	BL	BL	BL	BL	N/A	---	---	<b>PASS</b>
3	BL	BL	BL	BL	BL	---	---	<b>PASS</b>
4	BL	BL	BL	BL	BL	---	---	<b>PASS</b>
5	BL	BL	BL	BL	BL	---	---	<b>PASS</b>
6	BL	BL	BL	BL	BL	---	---	<b>PASS</b>
7	BL	BL	BL	BL	BL	---	---	<b>PASS</b>
8	BL	BL	BL	BL	BL	---	---	<b>PASS</b>
9	BL	BL	BL	BL	N/A	---	---	<b>PASS</b>
10	BL	BL	BL	BL	N/A	---	---	<b>PASS</b>

Test Item(s)	Dibutyl Phthalate (DBP) (mg/kg)	Benzylbutyl Phthalate (BBP) (mg/kg)	Bis-(2-ethylhexyl) Phthalate (DEHP) (mg/kg)	Diisobutyl phthalate (DIBP) (mg/kg)	Conclusion
CAS No.	84-74-2	85-68-7	117-81-7	84-69-5	
Limit	1000	1000	1000	1000	
No.	Result (mg/kg)				
3+4+5	N.D	N.D	N.D	N.D	PASS
6	N.D	N.D	N.D	N.D	PASS
8	N.D	N.D	N.D	N.D	PASS

Remark:

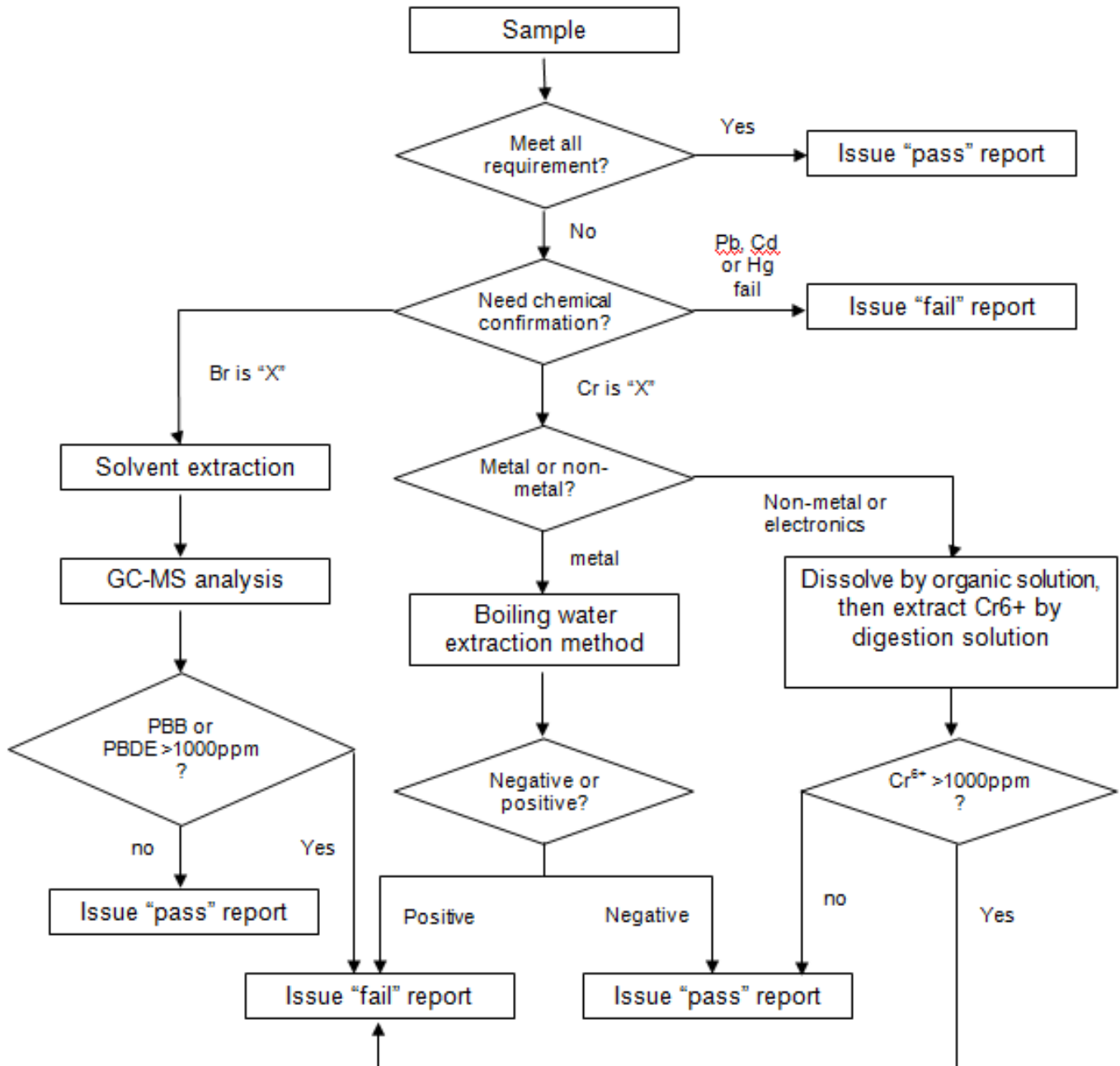
1. BL = below the limit
2. OL = over the limit
3. X = inconclusive, chemical confirm test is needed
4. NA = not applicable
5. mg/kg = milligram per kilogram = ppm
6. N.D = not detected
7. Negative = The Cr<sup>6+</sup> concentration is below the limit of quantification. The coating is considered a non- Cr<sup>6+</sup> based coating.
8. Positive = The Cr<sup>6+</sup> concentration is above the limit of quantification and the statistical margin of error, The sample coating is considered to contain Cr<sup>6+</sup>.
9. The limit for composite test should be divided by the mixed number.

Note:

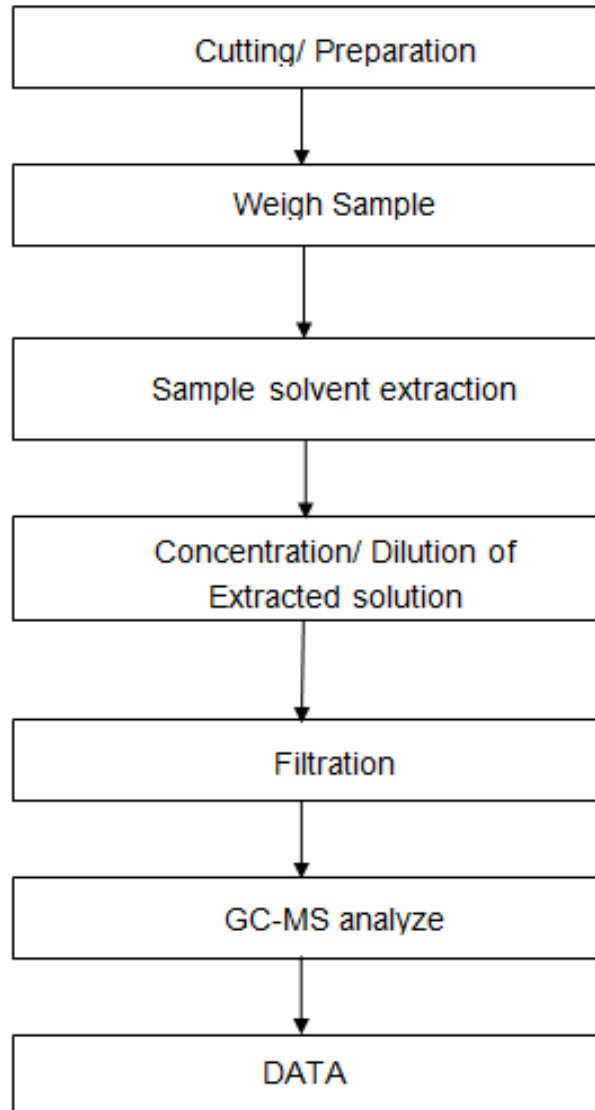
1. When perform screening tests, it is the result on total Br while test item on restricted substances is PBBs/PBDEs, it is the result on total Cr while test item on restricted substances is Cr<sup>6+</sup>.
2. Pb, Cd, Hg, Cr and Br results are obtained by EDXRF for primary screening, and further chemical testing by ICP-OES (for Cd, Pb, Hg), UV-VIS (for Cr<sup>6+</sup>) and GC-MS (for PBBs, PBDEs) is needed to be performed, if the concentration falls into the inconclusive area according to IEC 62321-3-1:2013.
3. For the XRF screening test for RoHS elements, the reading may be different to the actual content in the sample be of non-uniformity composition.

## Test flow chart

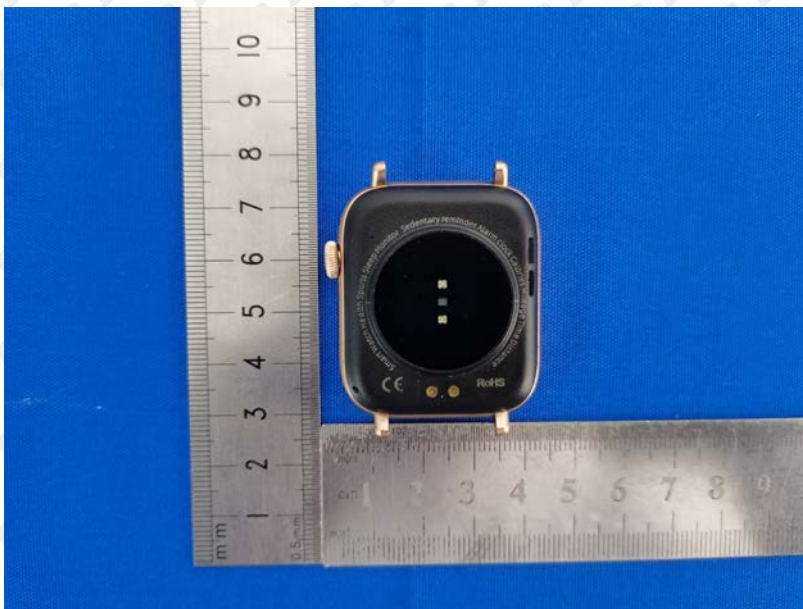
### 1. Pb/Cd/Hg/Cr<sup>6+</sup>/PBBs/PBDEs



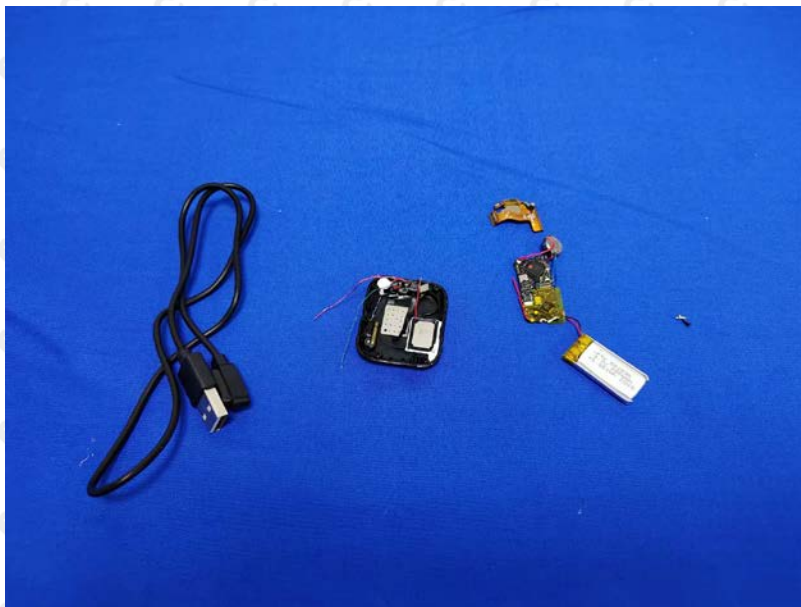
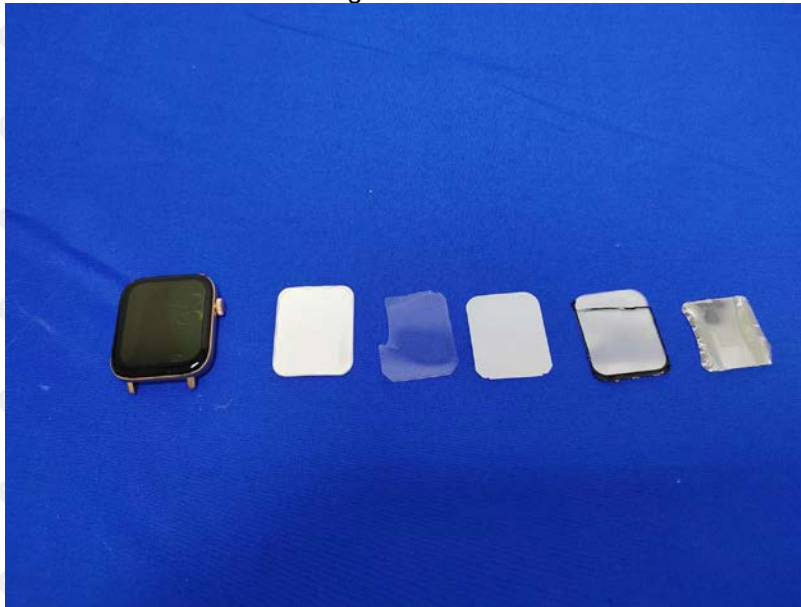
## 2. Phthalate test flow chart



## Photo documentation







\*\*\* End of Report \*\*\*

**CERTIFICATE OF CONFORMITY**

**EU - Restriction of the use of certain hazardous substances (RoHS) -  
No. CTB220623010CX -ZS**

**Applicant** : Shenzhen Xiangmingda Technology Co., Ltd.  
**Address** : 8F, Block A, Building C4, No.3 Industrial Park (Tianlong Industrial Zone), Huangbu Community, Hangcheng Street, Baoan District, Shenzhen  
**Manufacturer** : Shenzhen Xiangmingda Technology Co., Ltd.  
**Address** : 8F, Block A, Building C4, No.3 Industrial Park (Tianlong Industrial Zone), Huangbu Community, Hangcheng Street, Baoan District, Shenzhen  
**Product** : Smart Watch  
**Trade mark** : /  
**Model(s)** : See page 2  
**Test Report No.** : CTB220623010CX  
**Test Standards** : IEC 62321-3-1:2013, IEC 62321-4:2013+AMD1:2017, IEC 62321-5:2013, IEC 62321-6:2015, IEC 62321-7-1:2015 & IEC 62321-7-2:2017, IEC 62321-8:2017

The test results based on the above specified products comply with the EU RoHS Directive 2011/65 / EU Appendix II and amendment Directive (EU) 2015/863 limit on the restriction of the use of certain hazardous substances in electrical and electronic equipment.

The test results apply only to the particular sample tested and to the specific tests carried out.



Mick Wu (Chemical manager)  
June 23, 2021

This Declaration is for the exclusive use of CTB's Client and is provided pursuant to the agreement between CTB and its Client. The observations and test results referenced from this Declaration are relevant only to the sample tested. This Declaration by itself does not imply that the material, product, or service is or has ever been under a CTB certification program.

**Shenzhen CTB Testing Technology Co., Ltd**

Add: Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Community, Xinqiao Street, Baoan District, Shenzhen, Guangdong, China

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# CERTIFICATE OF CONFORMITY

EU - Restriction of the use of certain hazardous substances (RoHS) -  
No. CTB220623010CX -ZS

Series models as below (page 2) :

<b>Model(s)</b>	:	SW/29, T48, T49,T12, E300,S2, S2P, S3, S5,S6,S6P, S6T, S7, S8, S9, S10, T40, T42, T41, T41S, T42S,T43, T33S,T30,T46S, T32S, T34S, T45S, T60, T66, T11, T68, T69, T90, TW26, TW27, E86, E87, E88, E89, E80,E66, E10, E90, E98, E200, E400, E500, E510, E600, E800, E900, E88pro,E88mini, F100, F12,F100,F18, F45,F60,F11,F12, F28, F80, M6, M5, M4S, X5
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CERTIFICATE ◆ CERTIFICATE ◆ CERTIFICATE



**Shenzhen CTB Testing Technology Co., Ltd**

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